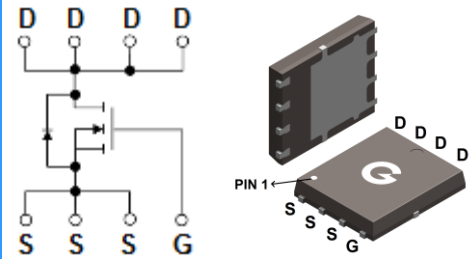


### Features

- Super low  $R_{DS(on)}$  and gate charge
- Advanced shielded-gate technology
- Green device available
- Excellent  $c_{dv}/d_t$  effect decline
- HBM: JESD22-A114-B: 1B

HF



PDFN5x6-8L

### Mechanical Data

- Case: PDFN5x6-8L
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208

### Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL018N04TH-5DL8	PDFN5x6-8L	5000 pcs / Tape & Reel	018N04TH

### Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DSS}$	40	V
Gate-to-Source Voltage	$V_{GSS}$	$\pm 20$	V
Continuous Drain Current ( $T_C = 25^\circ\text{C}$ )	$I_D$	200	A
Continuous Drain Current ( $T_C = 100^\circ\text{C}$ )		126	A
Continuous Drain Current ( $T_A = 25^\circ\text{C}$ ) <sup>*1</sup>		32	A
Continuous Drain Current ( $T_A = 100^\circ\text{C}$ ) <sup>*1</sup>		20	A
Pulsed Drain Current ( $t_p=10\mu\text{s}$ , $T_C = 25^\circ\text{C}$ )	$I_{DM}$	800	A
Single Pulse Avalanche Energy <sup>*3</sup>	$E_{AS}$	500	mJ
Power Dissipation ( $T_C = 25^\circ\text{C}$ )	$P_D$	114	W
Power Dissipation ( $T_A = 25^\circ\text{C}$ ) <sup>*1</sup>		3.1	W
Operating Junction Temperature Range	$T_J$	-55 ~ +150	$^\circ\text{C}$
Storage Temperature Range	$T_{STG}$	-55 ~ +150	$^\circ\text{C}$

### Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	1	1.1	$^\circ\text{C/W}$
Thermal Resistance Junction-to-Air <sup>*1</sup>	$R_{\theta JA}$	-	28	40	$^\circ\text{C/W}$

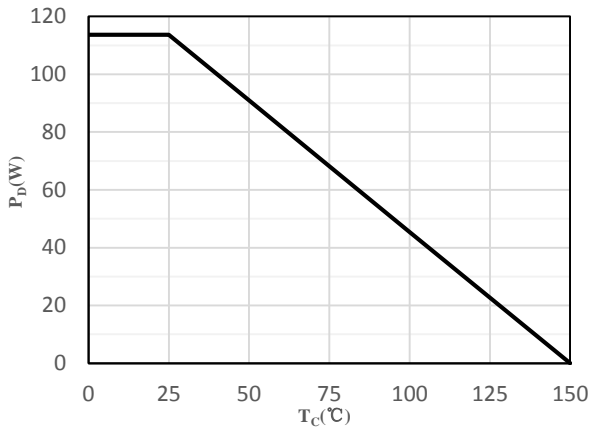
### Electrical Characteristics (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	40	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 40V, V_{GS} = 0V$	-	-	1	$\mu A$
$I_{GSS}$	Gate-Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$R_{DS(ON)}$	Drain-Source On-resistance <sup>*2</sup>	$V_{GS} = 10V, I_D = 50A$	-	1.5	1.8	m $\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3	4	V
$R_G$	Gate Resistance	$V_{GS} = 0V, f = 1MHz$	-	3.9	-	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{ISS}$	Input Capacitance	$V_{GS} = 0V$	-	4987	-	pF
$C_{OSS}$	Output Capacitance	$V_{DS} = 20V$	-	1654	-	
$C_{RSS}$	Reverse Transfer Capacitance	$f = 100kHz$	-	24	-	
<b>Switching Characteristics</b>						
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD} = 30V$	-	26	-	ns
$t_r$	Turn-on Rise Time	$V_{GS} = 15V$	-	73	-	
$t_{d(OFF)}$	Turn-Off Delay Time	$R_G = 3.3\Omega$	-	77	-	
$t_f$	Turn-Off Fall Time	$I_D = 30A$	-	88	-	
$Q_G$	Total Gate-Charge	$V_{DD} = 32V$	-	56	-	nC
$Q_{GS}$	Gate to Source Charge	$V_{GS} = 10V$	-	29	-	
$Q_{GD}$	Gate to Drain (Miller) Charge	$I_D = 150A$	-	6	-	
<b>Source-Drain Diode Characteristics</b>						
$V_{SD}$	Diode Forward Voltage <sup>*2</sup>	$I_{SD} = 50A, V_{GS} = 0V$	-	0.8	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_F = 20A, V_{GS} = 0V$	-	100	-	ns
$Q_{rr}$	Reverse Recovery Charge	$di/dt = 100A/\mu s$	-	200	-	nC

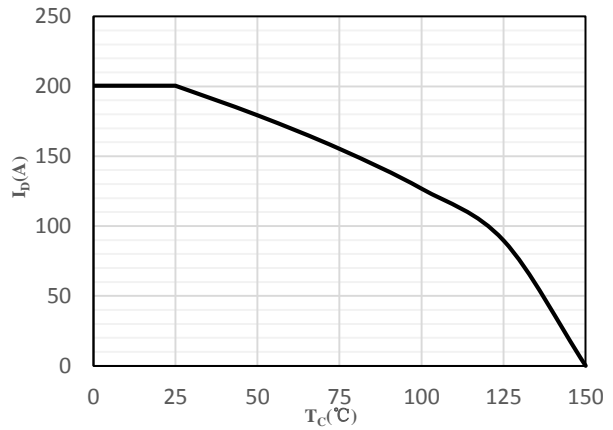
Notes:

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper
2. The data tested by pulsed, pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$
3. The  $E_{AS}$  data shows Max. rating. The test condition is  $V_{DD} = 30V, V_{GS} = 10V, L = 0.5mH$

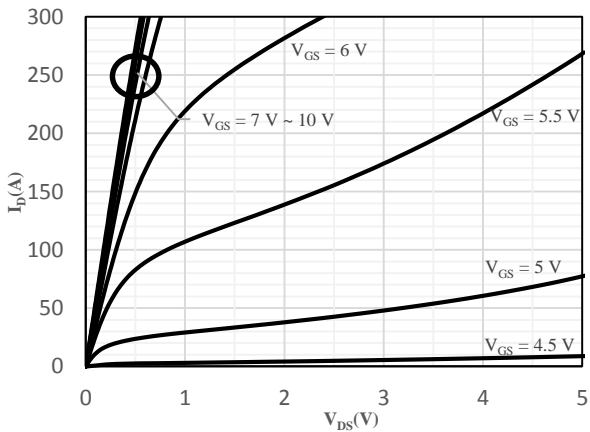
**Ratings and Characteristics Curves** (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)



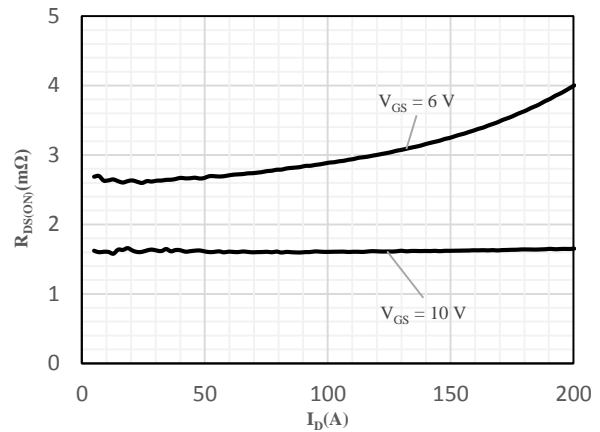
**Fig 1 Power Dissipation**



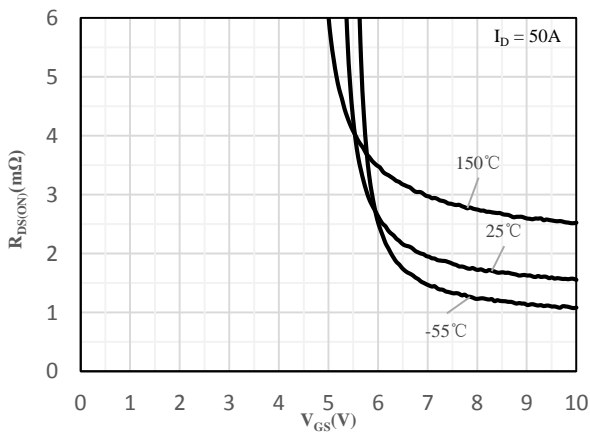
**Fig 2 Drain Current**



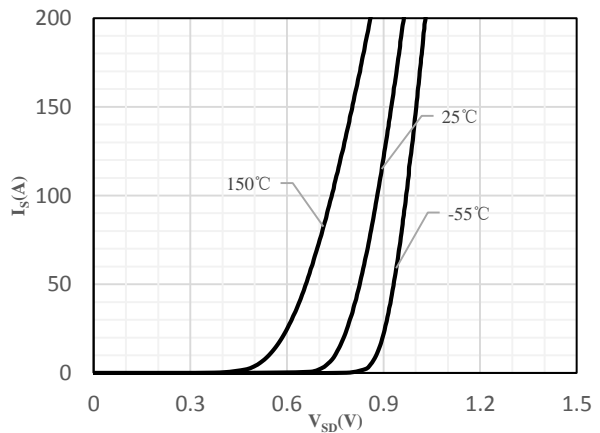
**Fig 3 Typical Output Characteristics**



**Fig 4 On-Resistance vs. Drain Current and Gate Voltage**



**Fig 5 On-Resistance vs. Gate-Source Voltage**



**Fig 6 Body-Diode Characteristics**

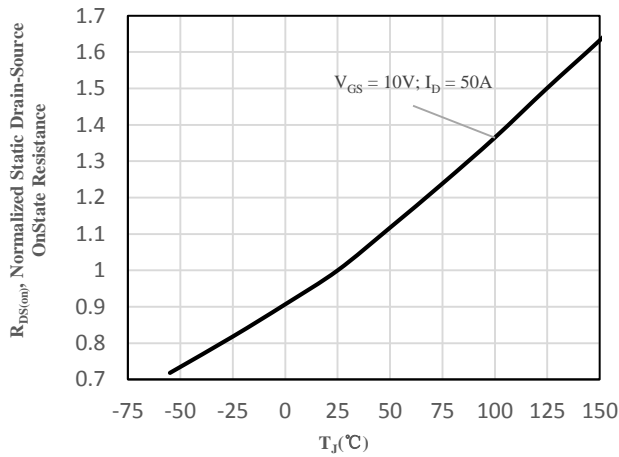


Fig 7 Normalized On-Resistance vs. Junction Temperature

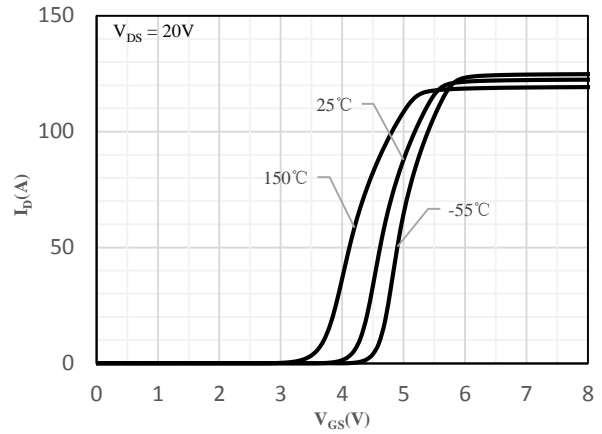


Fig 8 Transfer Characteristics

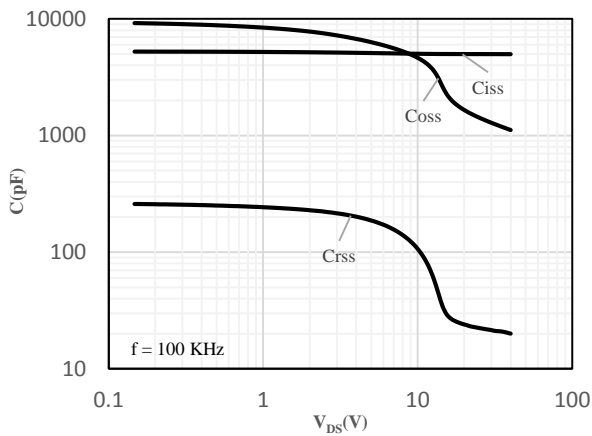


Fig 9 Capacitance Characteristics

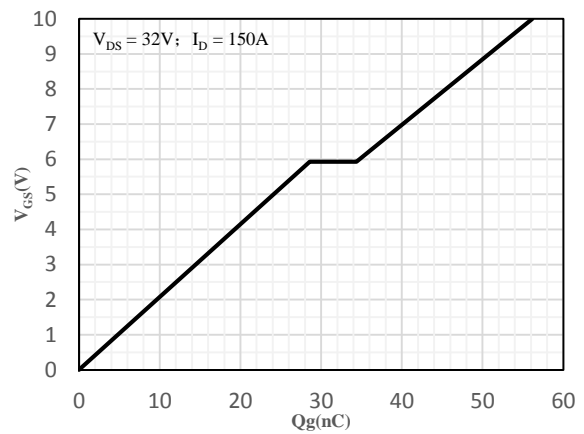


Fig 10 Gate-Charge Characteristics

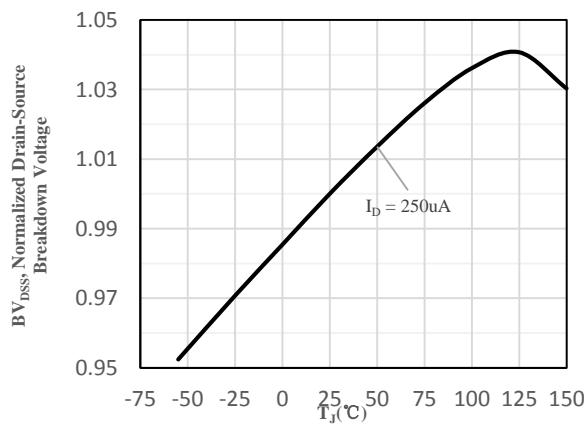


Fig 11 Normalized Breakdown Voltage vs. Junction Temperature

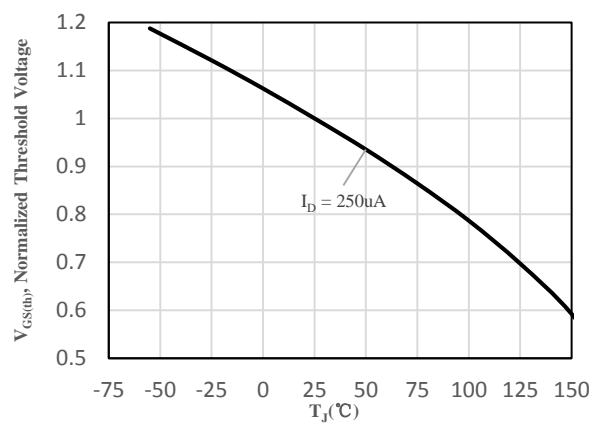


Fig 12 Normalized  $V_{GS(th)}$  vs. Junction Temperature

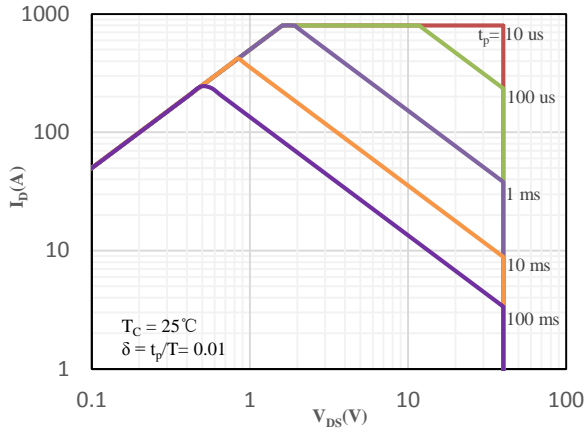


Fig 13 Safe Operation Area

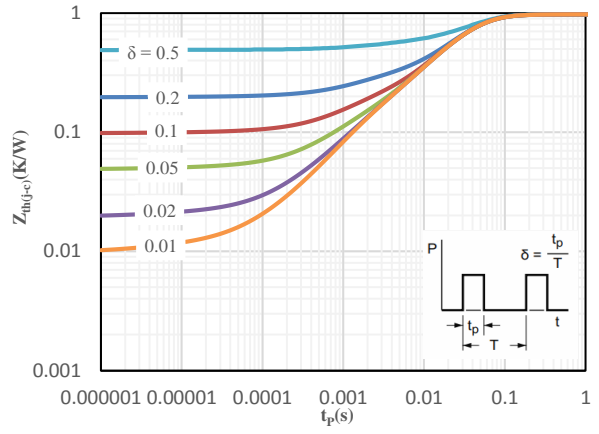
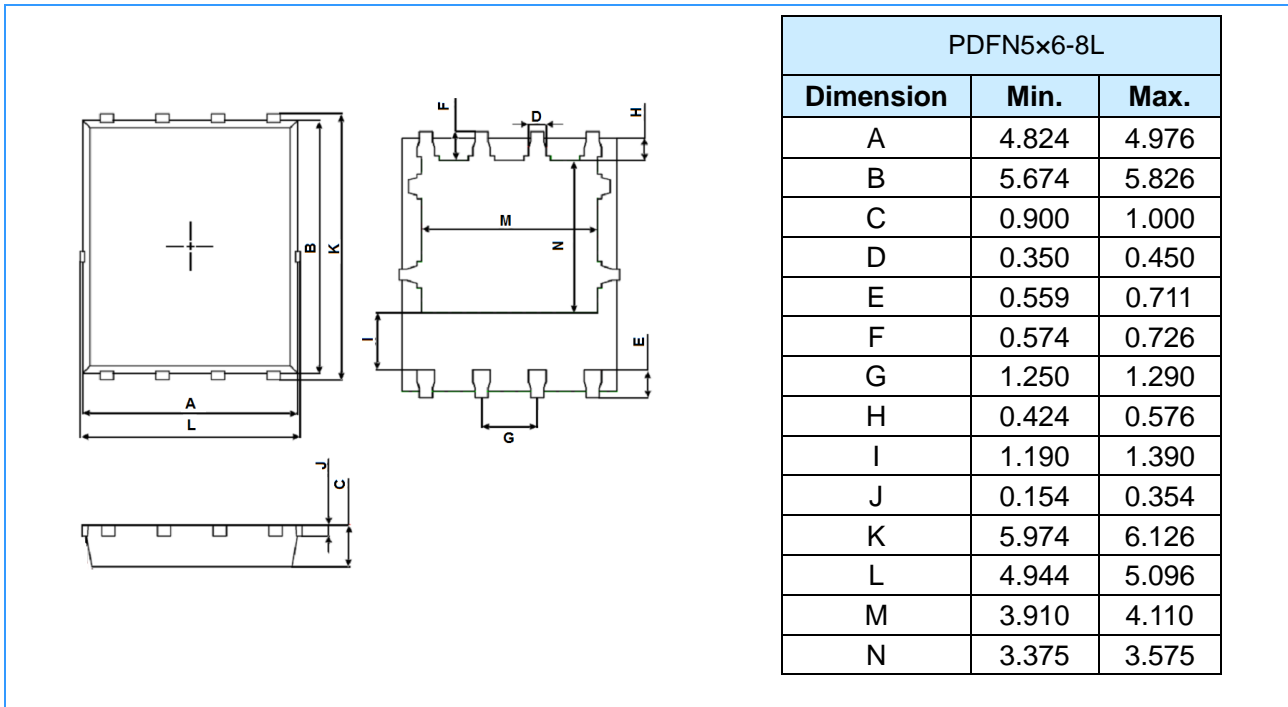
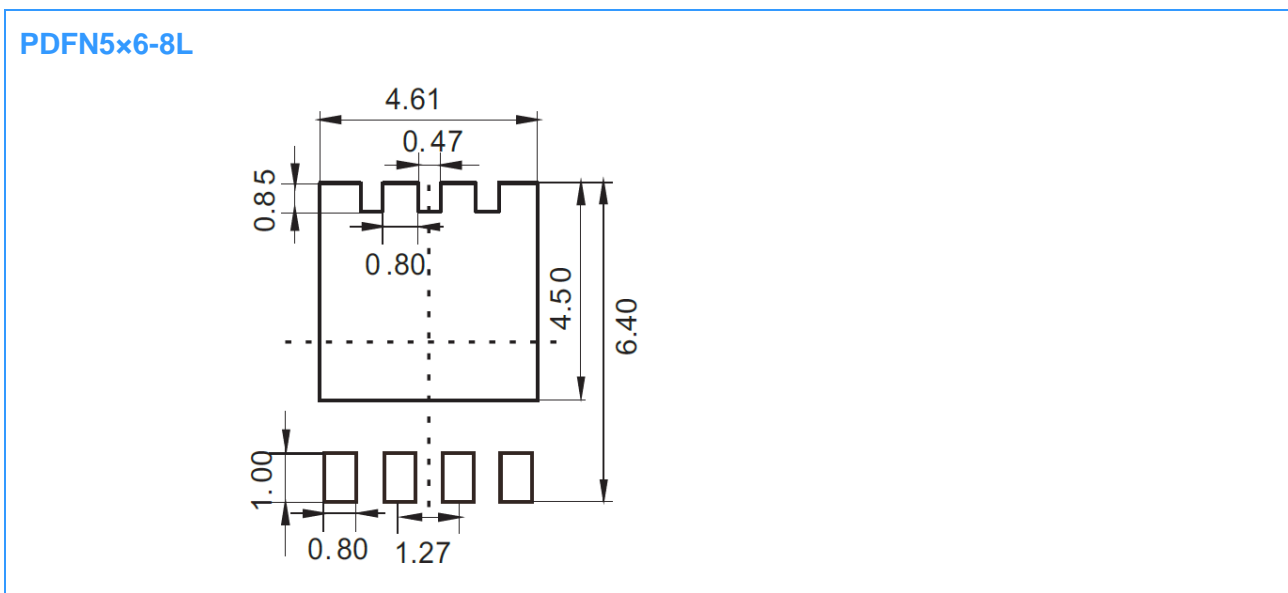


Fig 14 Maximum transient thermal impedance

**Package Outline Dimensions** (Unit: mm)



**Mounting Pad Layout** (Unit: mm)



**IMPORTANT NOTICE**

Changzhou Galaxy Century Microelectronics (GME) reserves the right to make changes without further notice to any product information (copyrighted) herein to make corrections, modifications, improvements, or other changes. GME does not assume any liability arising out of the application or use of any product described herein; neither does it convey any license under its patent rights, nor the rights of others.